Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
09/875,138	MIYAKE ET AL.
Examiner	Art Unit
Nhan T. Tran	2615

SEARCHED				
Class	Subclass	Date	Examiner	
			:	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	search - see ory printout	12/8/2005	NT

SEARCH NOT (INCLUDING SEARCH S)
	DATE	EXMR
Updated EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM)	12/8/2005	NT
348/14.\$.ccls. 379/\$.ccls. text search - see search history printout	12/8/2005	NT